Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/822,167	CHAE ET AL.	
Examiner	Art Unit	
Eric Wendler	2824	

SEARCHED					
Class	Subclass	Date	Examiner		
365	233	7/20/2006	EJW		
365	230.06	7/20/2006	EJW		
365	230.08	7/20/2006	EJW		
365	185.29	7/20/2006	EJW		
365	218	7/20/2006	EJW		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
365	233	7/20/2006	EJW		
365	230.06	7/20/2006	EJW		
365	230.08	7/20/2006	EJW		
365/185.29, 218		7/20/2006	EJW		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
See attached EAST search history	7/20/2006	EJW		
Consulted with examiner Andy Phung on class 365	7/20/2006	EJW		
				
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